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Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









June 2007

FGPF70N30TD 300V, 70A PDP IGBT

Features

- · High current capability
- Low saturation voltage: $V_{CE(sat)} = 1.5V @ I_C = 40A$
- · High input impedance
- · Fast switching
- · RoHS complaint

Application

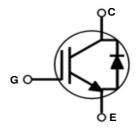
. PDP System



General Description

Using Novel Trench IGBT Technology, Fairchild's new sesries of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.





Absolute Maximum Ratings

Symbol	Description		Ratings	Units
V _{CES}	Collector-Emitter Voltage		300	V
V _{GES}	Gate-Emitter Voltage		±30	V
I _{C pulse(1)*}	Pulsed Collector Current	$@T_{C} = 25^{\circ}C$	160	A
	Maximum Power Dissipation	@ T _C = 25°C	49.2	W
P _D	Maximum Power Dissipation	$@ T_C = 100^{\circ}C$	19.7	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction-to-Case		2.54	°C/W
$R_{\theta JC}(DIODE)$	Thermal Resistance, Junction-to-Case for Diode		3.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Notes:

(1)Repetitive test , pluse width = 100usec , Duty = 0.1

^{*} Ic_pluse limited by max Tj

Package Marking and Ordering Information

Device Marking	Device	Package	Packaging Type	Qty per Tube	Max Qty per Box
FGPF70N30TD	FGPF70N30TDTU	TO-220F	Tube	50ea	-

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	V _{GE} = 0V, I _C = 250uA	300			V
$\Delta B_{VCES}/$ ΔT_J	Temperature Coefficient of Breakdown Voltage	V _{GE} = 0V, I _C = 250uA		0.2		V/°C
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			250	uA
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 400	nA
On Charac	eteristics					
V _{GE(th)}	G-E Threshold Voltage	I _C = 250uA, V _{CE} = V _{GE}	3.0	4.5	5.5	V
		I _C =20A, V _{GE} = 15V		1.2	1.5	V
V _{CE(sat)}	Collector to Emitter	I _C =40A, V _{GE} = 15V		1.5		V
	Saturation Voltage	I _C =70A, V _{GE} = 15V T _C = 25°C		1.8		V
		I _C = 70A, V _{GE} = 15V T _C = 125°C		1.9		V
Dynamic C	Characteristics					
C _{ies}	Input Capacitance			3000		pF
C _{oes}	Output Capacitance	$V_{CE} = 30V_{,} V_{GE} = 0V$ f = 1MHz		160		pF
C _{res}	Reverse Transfer Capacitance	1 - 1101112		110		pF
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time			32		ns
t _r	Rise Time	$V_{CC} = 200V, I_C = 40A$		90		ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 15\Omega$, $V_{GE} = 15V$ Resistive Load, $T_C = 25^{\circ}C$		175		ns
t _f	Fall Time			170	300	ns
t _{d(on)}	Turn-On Delay Time			30		ns
t _r	Rise Time	$V_{CC} = 200V$, $I_C = 40A$ $R_G = 15\Omega$, $V_{GE} = 15V$ Resistive Load, $T_C = 125^{\circ}C$		90		ns
t _{d(off)}	Turn-Off Delay Time			185		ns
t _f	Fall Time			235		ns
Qg	Total Gate Charge			125		nC
Q _{ge}	Gate-Emitter Charge	$V_{CE} = 200V, I_{C} = 40A$ $V_{GE} = 15V$		25		nC
Q _{gc}	Gate-Collector Charge			55		nC

Electrical Characteristics of DIODE $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
V	V _{FM} Diode Forward Voltage	I _F = 10A	T _C = 25°C		1.1	1.4	V
* FM			T _C = 125°C		0.9		
+	Diode Reverse Recovery Time	I _F = 10A dl/dt = 200A/μs Diode Forward Voltage	$T_C = 25^{\circ}C$		21		- ns
l _{rr} Diode Revers	Blode rieverse riccovery fillie		T _C = 125°C		35		
1	Diode Peak Reverse Recovery Cur-		T _C = 25°C		2.8		Α
'rr	rr rent		T _C = 125°C		5.6		^
Q _{rr}	Diode Reverse Recovery Charge		T _C = 25°C		29.4		nC
			T _C = 125°C		98		1.0

Typical Performance Characteristics

Figure 1. Typical Output Characteristics

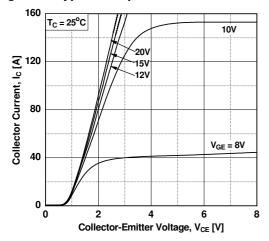


Figure 3. Typical Saturation Voltage Characteristics

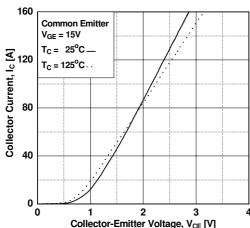


Figure 5. Saturation Voltage vs. Case
Temperature at Variant Current Level

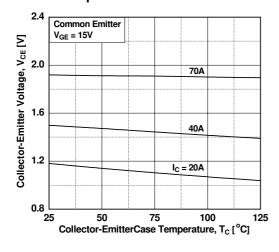


Figure 2. Typical Output Characteristics

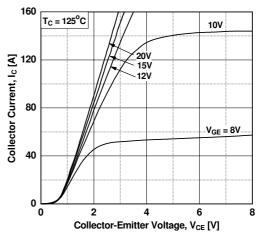


Figure 4. Transfer Characteristics

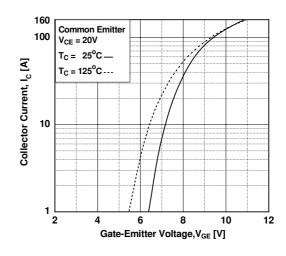
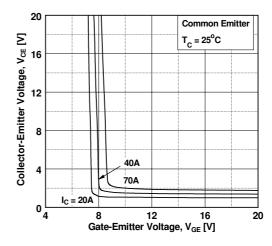


Figure 6. Saturation Voltage vs. V_{GE}



Typical Performance Characteristics (Continued)

Figure 7. Saturation Voltage vs. V_{GE}

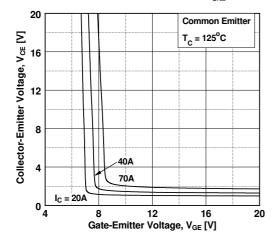


Figure 9. Gate Charge Characteristics

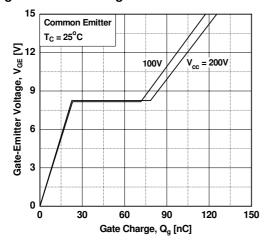


Figure 11. Turn-on Characteristics vs.
Gate Resistance

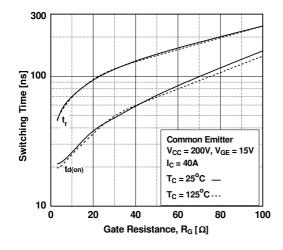


Figure 8. Capacitance Characteristics

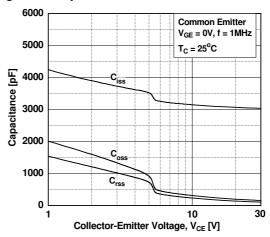


Figure 10. SOA Characteristics

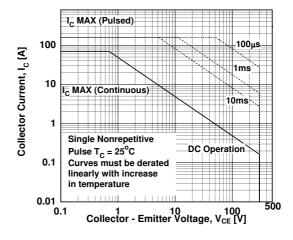
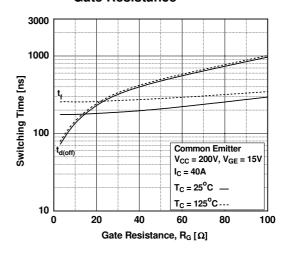


Figure 12. Turn-off Characteristics vs.
Gate Resistance



Typical Performance Characteristics (Continued)

Figure 13. Turn-on Characteristics vs. Collector Current

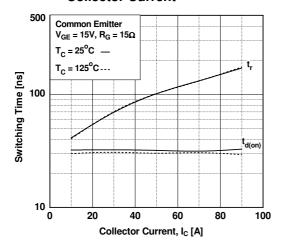


Figure 14. Turn-off Characteristics vs. Collector Current

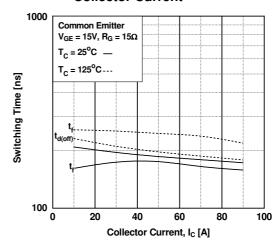


Figure 15. Switching Loss vs. Gate Resistance

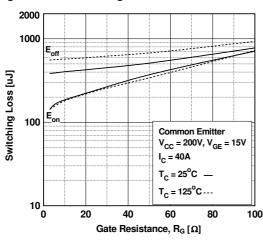


Figure 16. Switching Loss vs. Collector Current

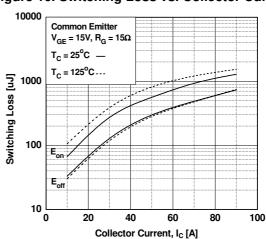
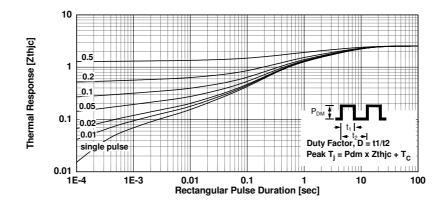


Figure 17. Transient Thermal Impedance of IGBT



Typical Performance Characteristics (Continued)

Figure 18. Forward Characteristics

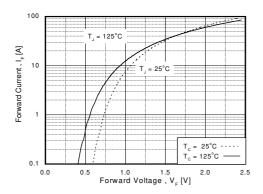


Figure 19. Typical Reverse Recovery Current

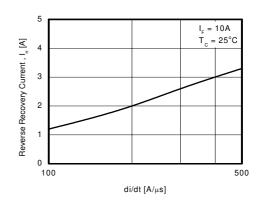
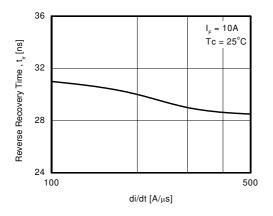
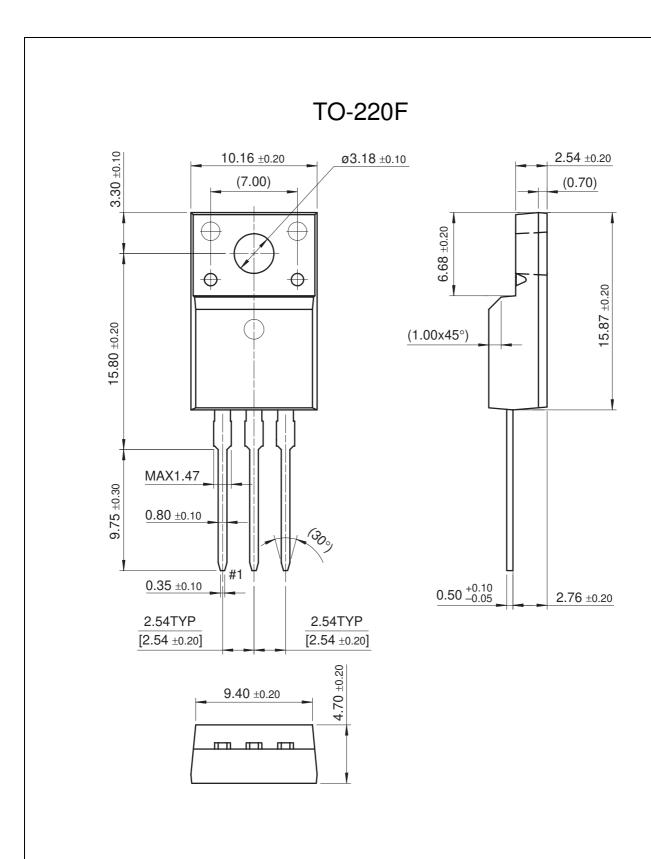


Figure 20. Typical Reverse Recovery Time









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